

Appendix A

Optimizing Total Power Consumption by Defining Total Noise and Total Nonlinearity

Using (2.6) and considering third order nonlinearity as the only dominant order of nonlinearity, $V_{int,tot}^2$ can be described as a function of $V_{IP3i,tot}^2$:

$$\bar{V}_{ni,tot}^2 = \frac{NPD - kTB}{B(R_s + R_{in})^2} \times 4R_s R_{in}^2 - \frac{V_{interferer}^6}{BV_{IP3i,tot}^4} \quad (A.1)$$

Replacing the result in (2.31), we have:

$$P_{tot} = \frac{BV_{IP3i,tot}^6}{\frac{NPD - kTB}{(R_s + R_{in})^2} \times 4R_s R_{in}^2 \times V_{IP3i,tot}^4 - V_{interferer}^6} \times \left(\sum_{m=1}^N \sqrt[3]{P_{Cm}} \right)^3 \quad (A.2)$$

Taking the derivative of P_{tot} with respect to $V_{IP3i,tot}^2$, we have:

$$\frac{\partial P_{tot}}{\partial (V_{IP3i,tot}^2)} = \frac{BV_{IP3i,tot}^4 \left(\frac{NPD - kTB}{(R_s + R_{in})^2} \times 4R_s R_{in}^2 \times V_{IP3i,tot}^4 - 3V_{interferer}^6 \right)}{\left(\frac{NPD - kTB}{(R_s + R_{in})^2} \times 4R_s R_{in}^2 \times V_{IP3i,tot}^4 - V_{interferer}^6 \right)^2} \times \left(\sum_{m=1}^N \sqrt[3]{P_{Cm}} \right)^3 \quad (A.3)$$

Setting (A.3) to zero, we have:

$$V_{IP3i,tot}^4 = \frac{3V_{interferer}^6}{\frac{NPD - kTB}{(R_s + R_{in})^2} \times 4R_s R_{in}^2} \quad (A.4)$$

Using (2.3) and (2.5), $V_{IMD3i,tot}$ can be obtained:

$$V_{IMD3i,tot}^2 = \frac{NPD - kTB}{(R_s + R_{in})^2} \times 4R_s R_{in}^2 \times \frac{1}{3} = \frac{BV_{ni,tot}^2}{2} \quad (A.5)$$

which results in (2.21).

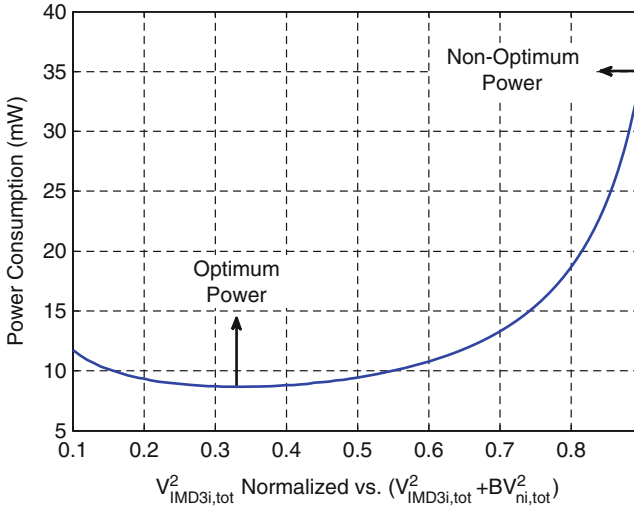


Fig. A.1 Power consumption given by the optimum-power design method as a function of $V^2_{IMD3i,tot}$ for a constant NPD.

Figure A.1 shows the power consumption of a receiver (described in detail in Sect. 2.8) as a function of $V^2_{IMD3i,tot}$. In other words, $V^2_{IMD3i,tot}$ and $BV^2_{ni,tot}$ are varied in a way that their sum remains constant so that NPD remains unchanged. For each value of $V^2_{IMD3i,tot}$ and $BV^2_{ni,tot}$ the power consumption is calculated according to optimum-power method using (2.31). Based on Fig. A.1, minimum power consumption is achieved when $V^2_{IMD3i,tot}$ constitutes one third of $(V^2_{IMD3i,tot} + BV^2_{ni,tot})$ which is in agreement with (2.21). In the extremes the power consumption can be much higher, for example when $V^2_{IMD3i,tot}$ comprises 90% of $(V^2_{IMD3i,tot} + BV^2_{ni,tot})$, the blocks need to be extremely low-noise and the power consumption can be more than four times higher than the minimum.

Glossary

Symbol	Description	Unit
A	Amplitude of the sinusoidal output of the VCO	V
A_v	Voltage conversion gain of the mixer	
$A_{vn,k}$	Voltage gain of the k^{th} stage at the signal band including the loading effects	
$A_{vn,k,image}$	Voltage gain of the k^{th} stage at the image band including the loading effects	
$A_{vn,tot}$	Voltage gain of the whole receiver at the signal band	
$A_{vn,tot,image}$	Voltage gain of the whole receiver at the image band	
B	Effective noise bandwidth	Hz
B_{CS}	B element of the T matrix of a transistor in common-source configuration	Ω
B_x	B element of the T matrix of a transistor in source-follower configuration	Ω
B_{sig}	Signal bandwidth	Hz
C_{max}	Maximum capacitance of the LC-tank	F
C_{min}	Minimum capacitance of the LC-tank	F
$C_{ImA,k}$	Ratio between the square of voltage gain at the image band to the square of voltage gain at the signal band calculated for the k^{th} stage	
$C_{ImN,k}$	Ratio between the square of the noise voltage at the image band to the square of the noise voltage at the signal band calculated for the k^{th} stage	
$C_{Distortion,q}(k)$	Contribution of the k^{th} stage to the total q^{th} order intermodulation distortion	V^2
c_{gd}	Gate-drain capacitance	F
c_{gs}	Gate-source capacitance	F
C_L	Load capacitance	F
C_{L1}	The capacitance seen from the positive node of the differential output	F
C_{L2}	The capacitance seen from the negative node of the differential output	F
$C_{Noise}(k)$	Contribution of the k^{th} stage to the total noise	V^2
C_{ox}	Oxide capacitance of a MOS transistor	F/m^2

(continued)

Symbol	Description	Unit
C_P	The equivalent capacitance after performing series-to-parallel conversion on the tank capacitance	F
C_s	Capacitances at the common source of the switching pair of the mixer	F
D_{CS}	D element of the T matrix of a transistor in common-source configuration	
D_x	D element of the T matrix of a transistor in source-follower configuration	
F	An empirical parameter called effective noise figure by Leeson	
G_1	First order Volterra kernel from RF current to the gate-source voltage of the mixer	Ω
G_2	Second order Volterra kernel from RF current to the gate-source voltage of the mixer	V/A^2
G_3	Second order Volterra kernel from RF current to the gate-source voltage of the mixer	V/A^3
g_{d0}	Transistor channel conductance when the drain-source voltage is zero	$1/\Omega$
g_m	First-order transconductance of the transistor	$1/\Omega$
g_{m2}	Second-order transconductance of the transistor	A/V^2
g_{m3}	Third-order transconductance of the transistor	A/V^3
G_C	Power conversion gain of the mixer	
G_T	Transducer power gain	
g_s	Inverse of R_S	$1/\Omega$
I_{DS}	Drain-source biasing current of the transistor	A
$I_{imd2,1}$	IMD2 current in the first branch of the differential output of the mixer	A
$I_{imd2,2}$	IMD2 current in the second branch of the differential output of the mixer	A
I_{imd2CM}	Common-mode output IMD2 current of the mixer	A
$I_{imd2Diff}$	Differential-mode output IMD2 current of the mixer	A
I_{Out}	Differential output current of the switching pair of the mixer	A
I_{Out3}	Third-order intermodulation content in the differential output current of the switching pair of the mixer	A
I_{pk}	The amplitude of the sinusoidal current	A
I_{RF}	RF current flowing into the switching pair of the mixer	A
IP3	Third order input intercept point	dBm
k	Boltzmann constant = 1.38×10^{-23}	J/K
k_c	Coupling factor between two inductors	
L_D	Drain inductance	H
L_G	Gate inductance	H
L_P	The equivalent inductance after performing series-to-parallel conversion on the tank inductance	H
L_S	Source inductance (connected to the source of the transistor)	H
M	Mutual inductance	H
MDS	Minimum detectable signal of a receiver (also known as sensitivity)	dBm
n	Turn ratio of a transformer	
N	Number of stages in the receiver	

(continued)

Symbol	Description	Unit
$N_{Antenna}$	Available noise power coming from the antenna	W
$N_{i,tot}$	The total available noise power due to the receiver referred to its input	W
NF_{tot}	Noise factor of the whole receiver	dB
NPD	Noise plus distortion of a receiver referred to its input	W
P	Power consumption of a stage	W
P_{Ck}	Power coefficient of the k^{th} stage: a proportionality constant relating the power consumption to the noise and linearity performance	W
$P_{IMDqi,tot}$	Equivalent input-referred available power of in-band q^{th} order intermodulation distortion due to an out-of-band interferer	W
P_S	Average power dissipated in the resistive part of the tank	W
P_{tot}	Power consumption of the whole receiver	W
Q	Effective quality factor of the tank	
Q_C	Quality factor of the tank capacitance	
Q_L	Quality factor of the tank inductance	
R_{CP}	Equivalent parallel resistance of the tank capacitance	Ω
R_{CS}	Series resistance of the tank capacitance	Ω
R_G	Gate resistance	Ω
R_{in}	Real part of the input impedance	Ω
R_L	Load resistance	Ω
R_{LP}	Equivalent parallel resistance of the tank inductance	Ω
R_{LS}	Series resistance of the tank inductance	Ω
r_o	Output resistance of the transistor	Ω
R_{out1}	The real part of the impedance seen from the positive node of the differential output	Ω
R_{out2}	The real part of the impedance seen from the negative node of the differential output	Ω
R_S	Source resistance	Ω
$S_x^{F(x)}$	Normalized single point sensitivity of F(x) to the variable x	
SNDR	Signal to noise-plus-distortion ratio	dB
T	Absolute temperature	K
T_0	Reference temperature for noise figure definition: 290°K	K
TR	Tuning range of a VCO	
U	Mason invariant: the gain of a linear two-port after unilateralization by embedding in a linear lossless reciprocal four-port	
V_{gs}	Gate-source voltage	V
$V_{imd2out}$	Differential output IMD2 voltage of the mixer	V
$V_{IMDqi,k}$	Equivalent input-referred voltage of the q^{th} order intermodulation distortion of the k^{th} stage of the receiver	V
$V_{IMDqi,tot}$	Equivalent input-referred voltage of the q^{th} order intermodulation distortion of the whole receiver	V
$V_{interferer}$	Voltage of worst-case out-of-band interferer signal at the input of the receiver	V
$V_{IPqi,k}$	Voltage of q^{th} order input intercept point of the k^{th} stage of the receiver	V
$V_{IPqi,tot}$	Voltage of q^{th} order input intercept point of the whole receiver	V
V_{LO}	Local oscillator voltage connected to the LO port of the mixer	V

(continued)

Symbol	Description	Unit
$V_{ni,k}$	Equivalent input-referred noise voltage of the k^{th} stage of the receiver	$V/\sqrt{\text{Hz}}$
$V_{ni,tot}$	Equivalent input-referred noise voltage of the whole receiver	$V/\sqrt{\text{Hz}}$
$V_{nout,k}$	Noise voltage due to the k^{th} stage at the output of the stage and at the signal band	$V/\sqrt{\text{Hz}}$
$V_{nout,k,image}$	Noise voltage due to the k^{th} stage at the output of the stage and at the image band	$V/\sqrt{\text{Hz}}$
V_{nout,R_s}	Noise at the output of the mixer due to the source resistance	$V/\sqrt{\text{Hz}}$
V_{nout,R_L}	Noise at the output of the mixer due to the load resistance	$V/\sqrt{\text{Hz}}$
$V_{nout,sw}$	Noise at the output of the mixer due to the switching pair	$V/\sqrt{\text{Hz}}$
$V_{nout,tot}$	Noise voltage due to the whole receiver at the output of the receiver and at the signal band	$V/\sqrt{\text{Hz}}$
$V_{nout,k,image}$	Noise voltage due to the whole receiver at the output of the receiver and at the image band	$V/\sqrt{\text{Hz}}$
V_{off}	Equivalent voltage offset representing the mismatch between the transistors in a differential pair	V
V_{out-}	Voltage of the negative node of the differential output	V
V_{out+}	Voltage of the positive node of the differential output	V
V_{RF}	RF voltage connected to the RF port of the mixer	V
V_T	Threshold voltage of a MOS transistor	V
W	Transistor width	m
X_{in}	Imaginary part of the input impedance	Ω
Z	Impedance matrix of a two-port	Ω
Z_{in}	Input impedance	Ω
Z_{L1}	The impedance seen from the positive node of the differential output	Ω
Z_{L2}	The impedance seen from the negative node of the differential output	Ω
Z_{src}	Source impedance	Ω
α_k	Contribution factor: the ratio between the noise (or distortion) contribution of the k^{th} stage to that of its following stage	
β	Proportionality constant between the current in an MOS transistor and the square of the difference between gate-source voltage and threshold voltage	A/V^2
γ	Transistor channel noise coefficient	
ΔNPD	Variations of the noise plus distortion of a receiver referred to its input	W
$\Delta V_{IPq_i,k}$	Variations of the voltage of q^{th} order input intercept point of the k^{th} stage of the receiver	V
$\Delta V_{ni,k}$	Variations of equivalent input-referred noise voltage of the k^{th} stage of the receiver	$V/\sqrt{\text{Hz}}$
ΔV_T	Absolute mismatch between the threshold voltage of the transistors in a differential pair	V
ΔZ_{in}	Variations of input impedance	Ω
δZ_L	Relative mismatch in the differential load impedance	
$\Delta \beta$	Absolute mismatch between the β of the transistors in a differential pair	A/V^2
$\Delta \theta$		$1/V$

(continued)

Symbol	Description	Unit
	Absolute mismatch between the θ of the transistors in a differential pair	
$\Delta\omega$	Offset from the oscillation angular frequency of the VCO	rad/s
$\Delta\omega_{1/f^3}$	Angular frequency of the corner between $1/f^3$ and $1/f^2$ regions	rad/s
θ	A fitting factor taking into account the short channel effects of MOS transistors	$1/V$
μ_n	The mobility of an NMOS transistor	$m^2/V/s$
τ	Time constant at the common-source node of the switching pair of the mixer	s
$\Phi(t)$	Phase of the sinusoidal output of a VCO	rad
$\Phi_{IMDqi,k}$	The phase of the equivalent input-referred voltage of the q^{th} order intermodulation distortion of the k^{th} stage	rad
$\Phi_{IMDqi,tot}$	The phase of the equivalent input-referred voltage of the q^{th} order intermodulation distortion of the whole receiver	rad
$\Phi_{IPqi,k}$	Phase of the voltage of the q^{th} order input intercept point of the k^{th} stage	V
$\Phi_{IPqi,tot}$	Phase of the voltage of the q^{th} order input intercept point of the whole receiver	V
$\Phi_{vn,k}$	The phase of the voltage gain of the k^{th} stage at the signal band including the loading effects	rad
$\Phi_{vn,tot}$	The phase of the voltage gain of the whole receiver at the signal band	rad
ω	Angular frequency	rad/s
ω_0	Oscillation angular frequency of a VCO	rad/s
ω_1	Angular frequency of the first tone in a multi-tone signal	rad/s
ω_2	Angular frequency of the second tone in a multi-tone signal	rad/s
ω_3	Angular frequency of the third tone in a multi-tone signal	rad/s
ω_{center}	Center (the middle of the maximum and minimum) angular frequency of oscillation of a VCO	rad/s
ω_{IF}	IF Angular frequency	rad/s
ω_{LO}	LO Angular frequency	rad/s
ω_{max}	Maximum angular frequency of oscillation of a VCO	rad/s
ω_{min}	Minimum angular frequency of oscillation of a VCO	rad/s

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